

Success story: GaN circuit research → radar and electronic warfare products

Microwave circuit research on GaN HEMT Technology and MMIC design between Saab AB and Chalmers has produced publications, 7 PhDs (yr 2012) and several state-of-the-art MMIC designs. MMIC circuit designs have then successfully been transferred to the soon to be released GaN process GH25 at UMS and then integrated into the next generation transmit-receive modules intended for future AESA-based radar and electronic warfare systems.

"Ghz Centre, and its predecessor CHACH, has offered an important possibility to gain early design experience in an emerging semiconductor technology even before it is commercially available. The lead time in introducing this new technology into several new systems has thus been shortened by several years." Johan Carlert, Manager Technology Strategies & MMIC design, Microwave & Antennas, Saab AB

Research Chalmers-Saab:



An AlGaIn/GaN HEMT-Based Microstrip MMIC Process for Advanced Transceiver Design

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Abstract—A MMIC process in AlGaIn/GaN technology for advanced transceiver design has been developed. The process is based on microstrip technology with a complete model library of passive elements and AlGaIn/GaN HEMTs. The transceiver technology in this process is suitable for both gain and low noise design, demonstrated with a power density of 5 W/mm, and an NF_{min} of 1.4 dB at X-band. Process capability of submicron, complementary to power amplifiers and LNAs, in a transceiver system have been investigated. The results indicate that an all AlGaIn/GaN MMIC transceiver is realizable using this technology.

Index Terms—Amplifier, gallium nitride (GaN), mixer, monolithic microwave integrated circuit (MMIC), switch.

I. INTRODUCTION

WIDE-BANDGAP electronics show great potential to become the next generation of solid-state technology for high-power microwave applications. With power densities far beyond that of traditional technologies, i.e., GaAs pseudomorphic HEMT (pHEMT) and Si LDMOS, and high efficiencies [1]–[3], AlGaIn/GaN-based circuits are well suited for radar and transceiver systems.

AlGaIn/GaN HEMT-based high-power microwave electronics have been extensively researched over the past years. Power amplifiers in code-division multiple access (CDMA) operation at 2 GHz [4], [5], as well as monolithic microwave integrated circuits (MMICs) operating at X-band [2], [3], [6] have shown excellent performance. The high power-handling capabilities also makes GaN suitable for receiver electronics where the high component breakdown voltage makes the circuits inherently robust [7]–[10]. The high linearity of circuits

based on AlGaIn/GaN HEMTs also ensures a high dynamic range of the receiver electronics [11]. The demonstration of low-loss switches in AlGaIn/GaN technology [12] indicates the possibility to fabricate entire transceivers on one chip. The combination of high power density, high efficiency, moderate noise figure, and robustness opens up new possibilities in the design of radar transceivers. For example, even though the noise figure of GaN technology is inferior to that of an optimized GaAs pHEMT, the overall transceiver noise performance may be much improved over the GaAs implementation. This is possible since the robustness of a GaN-based low-noise amplifier (LNA) may facilitate the omission of trimmer/peaking circuitry in the receiver path.

To realize multifunction chips, process repeatability and uniformity are essential. Demonstrative circuits have been fabricated using an in-house process, which represent transceiver functions such as transmitter/receiver (TR) switches, wideband gain blocks, and mixers. The output power and low noise performance of the in-house technology are demonstrated by load-pull and noise-figure measurements. The results indicate that a fully integrated transceiver is feasible.

In this paper, we present a GaN MMIC process in detail (process, uniformity), together with a set of transceiver MMIC fabricated on the same ep-wafer in the same batch. This comprehensive presentation of both process and MMIC results facilitates assessment of a fully integrated GaN transceiver.

II. MMIC PROCESS

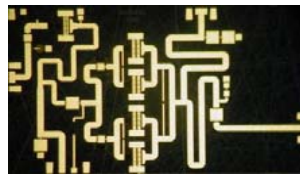
The research is based on the previous development of an in-house SiC MMIC process [13]. As the substrate technology and electrical requirements of SiC MESFETs and AlGaIn/GaN HEMTs are similar, a common back-end process is feasible.

The transceiver is fabricated using an AlGaIn/GaN heterostructure grown on semiconducting SiC. The material is supplied by commercial vendors (Cree Inc., Durham, NC, and NVE/ATE, Tokyo, Japan) and through the Korean project [14]. The epitaxial structure consists of a 25-nm AlGaIn/GaN layer on top of a 2-μm undoped GaN buffer on semiconducting SiC. This structure typically results in a sheet carrier density of 1.0 · 10¹⁹ cm⁻² and a mobility of 1200 cm²/Vs according to Hall measurements.

The photo lithography is made using an ASML PAS 2500/40 stepper modified for processing of 2- and 3-μm wafers, giving an overlay accuracy of 150 nm and a resolution of 0.7 μm.

The HEMT is defined and isolated through mesa etching using a chlorine-based inductively coupled plasma (ICP) reactive ion etching (RIE) process. The source-drain separation

MMIC high power amplifier design by Saab and Chalmers, and processed in the GH25 process at UMS



Exploitation:

